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10475,193LIST OF ART CITED BY APPLICANT  
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## U.S. PATENT DOCUMENTS

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|-------------------|----|-----------------|-------|--------|-------|----------|----------------------------|
| 4/4               | AA | 6,233,159 B1    | 07/01 | Thakur |       |          |                            |
|                   | AB |                 |       |        |       |          |                            |
|                   | AC |                 |       |        |       |          |                            |
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|                   | AF |                 |       |        |       |          |                            |
|                   | AG |                 |       |        |       |          |                            |
|                   | AH |                 |       |        |       |          |                            |
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|                   | AJ |                 |       |        |       |          |                            |
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|  | AM |                 |      |         |       |          |             |    |
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|  | AP |                 |      |         |       |          |             |    |
|  | AQ |                 |      |         |       |          |             |    |

## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

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|                   | AD |                   |         |           |       |          |                            |
|                   | AE |                   |         |           |       |          |                            |
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